## FEATURES

High Off Isolation -75 dB at 100 MHz
-3 dB Signal Bandwidth $\mathbf{3 0 0}$ MHz
+1.8 V to +5.5 V Single Supply
Low On-Resistance (15 $\Omega$ )
Fast Switching Times
$t_{\text {on }}$ Typically 9 ns
$t_{\text {off }}$ Typically 3 ns
Typical Power Consumption <0.01 $\mu \mathrm{W}$
TTL/CMOS Compatible

## APPLICATIONS

Audio and Video Switching
RF Switching
Networking Applications
Battery Powered Systems
Communication Systems
Relay Replacement
Sample-and-Hold Systems

## GENERAL DESCRIPTION

The ADG751 is a low voltage SPST (single pole, single throw) switch. It is constructed in a T-switch configuration, which results in excellent Off Isolation while maintaining good frequency response in the ON condition.
High off isolation and wide signal bandwidth make this part suitable for switching RF and video signals. Low power consumption and operating supply range of +1.8 V to +5.5 V make it ideal for battery powered, portable instruments.
The ADG751 is designed on a submicron process that provides low power dissipation yet gives high switching speed and low on resistance. This part is a fully bidirectional switch and can handle signals up to and including the supply rails.
The ADG751 is available in 6-lead SOT-23 and 8-lead $\mu$ SOIC packages.

## REV. A

## FUNCTIONAL BLOCK DIAGRAM



SWITCH SHOWN FOR A LOGIC "1" INPUT

## PRODUCT HIGHLIGHTS

1. High Off Isolation -75 dB at 100 MHz .
2. -3 dB Signal Bandwidth 300 MHz .
3. Low On-Resistance ( $15 \Omega$ ).
4. Low Power Consumption, typically $<0.01 \mu \mathrm{~W}$.
5. Tiny 6 -lead SOT-23 and 8 -lead $\mu$ SOIC packages.


| Parameter | B Grade |  | A Grade |  | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | $+25^{\circ} \mathrm{C}$ |  | $+25^{\circ} \mathrm{C}$ |  |  |  |
| ANALOG SWITCH <br> Analog Signal Range On-Resistance ( $\mathrm{R}_{\mathrm{ON}}$ ) On-Resistance Flatness ( $\mathrm{R}_{\text {Flat(ON) }}$ ) | 28 35 3 | $\begin{aligned} & 0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}} \\ & 40 \\ & 5 \end{aligned}$ | $\begin{aligned} & 15 \\ & 18 \\ & 2 \end{aligned}$ | $\begin{aligned} & 0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}} \\ & 20 \\ & 3 \end{aligned}$ | V <br> $\Omega$ typ <br> $\Omega$ max <br> $\Omega$ typ <br> $\Omega$ max | $\mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, \mathrm{I}_{\mathrm{DS}}=10 \mathrm{~mA} ;$ <br> Test Circuit 1 $\begin{aligned} & \mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } 2.5 \mathrm{~V}, \mathrm{I}_{\mathrm{DS}}=10 \mathrm{~mA} \\ & \mathrm{~V}_{\mathrm{DD}}=4.5 \mathrm{~V} \end{aligned}$ |
| LEAKAGE CURRENTS <br> Source OFF Leakage $\mathrm{I}_{\mathrm{S}}$ (OFF) <br> Drain OFF Leakage $\mathrm{I}_{\mathrm{D}}(\mathrm{OFF})$ <br> Channel ON Leakage $\mathrm{I}_{\mathrm{D}}, \mathrm{I}_{\mathrm{S}}(\mathrm{ON})$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \end{aligned}$ | $\begin{gathered} \pm 3.0 \\ \pm 3.0 \\ \pm 3.0 \end{gathered}$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \end{aligned}$ | $\begin{gathered} \pm 3.0 \\ \pm 3.0 \\ \pm 3.0 \end{gathered}$ | nA typ nA max nA typ nA max nA typ nA max | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+5.5 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{D}}=4.5 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=1 \mathrm{~V} / 4.5 \mathrm{~V} \end{aligned}$ <br> Test Circuit 2 $\mathrm{V}_{\mathrm{D}}=4.5 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=1 \mathrm{~V} / 4.5 \mathrm{~V} \text {; }$ <br> Test Circuit 2 $\mathrm{V}_{\mathrm{D}}=\mathrm{V}_{\mathrm{S}}=1 \mathrm{~V} \text {, or } 4.5 \mathrm{~V} \text {; }$ <br> Test Circuit 3 |
| DIGITAL INPUTS <br> Input High Voltage, $\mathrm{V}_{\text {INH }}$ Input Low Voltage, $\mathrm{V}_{\text {INL }}$ Input Current $\mathrm{I}_{\mathrm{INL}}$ or $\mathrm{I}_{\mathrm{INH}}$ <br> $\mathrm{C}_{\mathrm{IN}}$, Digital Input Capacitance | $0.001$ <br> 2 | $\begin{gathered} 2.4 \\ 0.8 \\ \\ \pm 0.5 \end{gathered}$ | $0.001$ $2$ | $\begin{aligned} & 2.4 \\ & 0.8 \\ & \\ & \pm 0.5 \end{aligned}$ | V min <br> V max <br> $\mu \mathrm{A}$ typ <br> $\mu \mathrm{A}$ max <br> pF typ | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {INL }}$ or $\mathrm{V}_{\text {INH }}$ |
| DYNAMIC CHARACTERISTICS ${ }^{1}$ <br> $\mathrm{t}_{\mathrm{ON}}$ <br> $\mathrm{t}_{\text {OFF }}$ <br> Charge Injection <br> Off Isolation <br> -3 dB Bandwidth <br> $\mathrm{C}_{\mathrm{S}}$ (OFF) <br> $\mathrm{C}_{\mathrm{D}}$ (OFF) <br> $\mathrm{C}_{\mathrm{D}}, \mathrm{C}_{\mathrm{S}}(\mathrm{ON})$ | $\begin{aligned} & 9 \\ & 3 \\ & 1 \\ & -75 \\ & -180 \\ & 4 \\ & 4 \\ & 26 \end{aligned}$ | 13 | $\begin{aligned} & 9 \\ & 3 \\ & 1 \\ & -65 \\ & 300 \\ & 4 \\ & 4 \\ & 15 \end{aligned}$ | 13 | ns typ ns max ns typ ns max pC typ dB typ <br> MHz typ pF typ pF typ pF typ | $\mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF} ;$ <br> $\mathrm{V}_{\mathrm{S}}=3 \mathrm{~V}$, Test Circuit 4 <br> $\mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF}$; <br> $\mathrm{V}_{\mathrm{S}}=3 \mathrm{~V}$, Test Circuit 4 <br> $\mathrm{V}_{\mathrm{S}}=1 \mathrm{~V}, \mathrm{R}_{\mathrm{S}}=0 \Omega, \mathrm{C}_{\mathrm{L}}=1.0 \mathrm{nF} ;$ <br> Test Circuit 5 $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}, \mathrm{f}=100 \mathrm{MHz}$ <br> Test Circuit 6 <br> $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}$, Test Circuit 7 |
| POWER REQUIREMENTS $\mathrm{I}_{\mathrm{DD}}$ | $\begin{aligned} & 0.001 \\ & 0.1 \end{aligned}$ | 0.5 | $\begin{aligned} & 0.001 \\ & 0.1 \end{aligned}$ | 0.5 | $\mu \mathrm{A}$ typ <br> $\mu \mathrm{A}$ max | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+5.5 \mathrm{~V} \\ & \text { Digital Inputs }=0 \mathrm{~V} \text { or }+5.5 \mathrm{~V} \end{aligned}$ |

## NOTES

${ }^{1}$ Guaranteed by design, not subject to production test
Specifications subject to change without notice.

| Parameter | B Grade |  | A Grade |  | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $\begin{aligned} & -40^{\circ} \mathrm{C} \text { to } \\ & +85^{\circ} \mathrm{C} \end{aligned}$ |  | $\begin{aligned} & -40^{\circ} \mathrm{C} \text { to } \\ & +85^{\circ} \mathrm{C} \end{aligned}$ |  |  |
| ANALOG SWITCH Analog Signal Range On-Resistance ( $\mathrm{R}_{\mathrm{ON}}$ ) | 60 | $\begin{aligned} & 0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}} \\ & 90 \end{aligned}$ | 35 | $\begin{aligned} & 0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}} \\ & 50 \end{aligned}$ | V <br> $\Omega$ typ <br> $\Omega$ max | $\mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, \mathrm{I}_{\mathrm{DS}}=-10 \mathrm{~mA} ;$ <br> Test Circuit 1 |
| LEAKAGE CURRENTS <br> Source OFF Leakage $\mathrm{I}_{\mathrm{S}}$ (OFF) <br> Drain OFF Leakage $\mathrm{I}_{\mathrm{D}}(\mathrm{OFF})$ <br> Channel ON Leakage $\mathrm{I}_{\mathrm{D}}, \mathrm{I}_{\mathrm{S}}(\mathrm{ON})$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \end{aligned}$ | $\begin{aligned} & \pm 3.0 \\ & \pm 3.0 \\ & \pm 3.0 \end{aligned}$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \\ & \pm 0.01 \\ & \pm 0.25 \end{aligned}$ | $\begin{aligned} & \pm 3.0 \\ & \pm 3.0 \\ & \pm 3.0 \end{aligned}$ | nA typ $n A \max$ nA typ nA max nA typ nA max | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{D}}=3 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=1 \mathrm{~V} / 3 \mathrm{~V} \end{aligned}$ <br> Test Circuit 2 $\mathrm{V}_{\mathrm{D}}=1 \mathrm{~V} / 3 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=3 \mathrm{~V} / 1 \mathrm{~V} ;$ <br> Test Circuit 2 $\mathrm{V}_{\mathrm{D}}=\mathrm{V}_{\mathrm{S}}=1 \mathrm{~V} \text {, or } 3 \mathrm{~V} \text {; }$ <br> Test Circuit 3 |
| DIGITAL INPUTS <br> Input High Voltage, $\mathrm{V}_{\text {INH }}$ Input Low Voltage, $\mathrm{V}_{\text {INL }}$ Input Current $\mathrm{I}_{\mathrm{INL}}$ or $\mathrm{I}_{\text {INH }}$ <br> $\mathrm{C}_{\text {IN }}$, Digital Input Capacitance | $0.001$ <br> 2 | $\begin{gathered} 2.0 \\ 0.4 \\ \\ \pm 0.5 \end{gathered}$ | $0.001$ $2$ | $\begin{aligned} & 2.0 \\ & 0.4 \\ & \\ & \pm 0.5 \end{aligned}$ | V min <br> V max <br> $\mu \mathrm{A}$ typ $\mu \mathrm{A}$ max pF typ | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\text {INL }}$ or $\mathrm{V}_{\text {INH }}$ |
| DYNAMIC CHARACTERISTICS ${ }^{1}$ <br> $\mathrm{t}_{\mathrm{ON}}$ <br> $\mathrm{t}_{\mathrm{OFF}}$ <br> Charge Injection <br> Off Isolation <br> -3 dB Bandwidth <br> $\mathrm{C}_{\mathrm{S}}$ (OFF) <br> $\mathrm{C}_{\mathrm{D}}$ (OFF) <br> $\mathrm{C}_{\mathrm{D}}, \mathrm{C}_{\mathrm{S}}(\mathrm{ON})$ | 12 <br> 4 <br> 1 <br> $-75$ <br> 180 <br> 4 <br> 4 <br> 26 | 19 6 | $\begin{aligned} & 12 \\ & 4 \\ & 1 \\ & -65 \\ & \\ & 280 \\ & 4 \\ & 4 \\ & 15 \end{aligned}$ | 19 | ns typ ns max ns typ ns max pC typ dB typ <br> MHz typ <br> pF typ pF typ pF typ | $\mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF}$; <br> $\mathrm{V}_{\mathrm{S}}=2 \mathrm{~V}$, Test Circuit 4 <br> $\mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF}$; <br> $\mathrm{V}_{\mathrm{S}}=2 \mathrm{~V}$, Test Circuit 4 <br> $\mathrm{V}_{\mathrm{S}}=1 \mathrm{~V}, \mathrm{R}_{\mathrm{S}}=0 \Omega, \mathrm{C}_{\mathrm{L}}=1.0 \mathrm{nF}$; <br> Test Circuit 5 $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}, \mathrm{f}=100 \mathrm{MHz} ;$ <br> Test Circuit 6 <br> $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}$, Test Circuit 7 |
| POWER REQUIREMENTS $\mathrm{I}_{\mathrm{DD}}$ | $\begin{aligned} & 0.001 \\ & 0.1 \end{aligned}$ | 0.5 | $\begin{aligned} & 0.001 \\ & 0.1 \end{aligned}$ | 0.5 | $\mu \mathrm{A}$ typ <br> $\mu \mathrm{A}$ max | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V} \\ & \text { Digital Inputs }=0 \mathrm{~V} \text { or }+3.3 \mathrm{~V} \end{aligned}$ |

## NOTES

${ }^{1}$ Guaranteed by design, not subject to production test.
Specifications subject to change without notice.

| ABSOLUTE MAXIMUM RATINGS ${ }^{1}$ <br> ( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ unless otherwise noted) |  |
| :---: | :---: |
| $\mathrm{V}_{\mathrm{DD}}$ to GND . . . . . . . . . . . . . . . . . . . . . . . . - 0.3 V to +6 V |  |
| Analog, Digital Inputs ${ }^{2} \ldots \ldots \ldots \ldots,-0.3 \mathrm{~V}$ to $\mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V}$ or30 mA, Whichever Occurs First |  |
| Peak Current, S or D $\ldots \begin{gathered}\text {. . . . . . . . . . . . . . . . . . . . } 100 \mathrm{~mA} \\ \text { (Pulsed at } 1 \mathrm{~ms}, 10 \% \text { Duty Cycle Max) }\end{gathered}$ |  |
| Continuous Current, S or D | 30 mA |
| Operating Temperature Range |  |
| Industrial (A, B Versions) | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Junction Temperature ( $\mathrm{T}_{\mathrm{J}}$ Max) | . $+150^{\circ} \mathrm{C}$ |
| Power Dissipation | $\left(\mathrm{T}_{\mathrm{J}} \mathrm{Max}-\mathrm{T}_{\mathrm{A}}\right) / \theta_{\mathrm{JA}}$ |
| $\mu$ SOIC Package |  |
| $\theta_{\text {JA }}$ Thermal Impedance | $206^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\theta_{\text {JC }}$ Thermal Impedance | $44^{\circ} \mathrm{C} / \mathrm{W}$ |

## SOT-23 Package

$\theta_{\mathrm{JA}}$ Thermal Impedance . . . . . . . . . . . . . . . . . . . . . $229.6^{\circ} \mathrm{C} / \mathrm{W}$
$\theta_{\text {JC }}$ Thermal Impedance . . . . . . . . . . . . . . . . . . . . $91.99^{\circ} \mathrm{C} / \mathrm{W}$
Lead Temperature, Soldering
Vapor Phase (60 sec) . . . . . . . . . . . . . . . . . . . . . . . . . $+215^{\circ} \mathrm{C}$
Infrared (15 sec) . . . . . . . . . . . . . . . . . . . . . . . . . . . . $+220^{\circ} \mathrm{C}$

## NOTES

${ }^{1}$ Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.
${ }^{2}$ Overvoltages at IN, S or D will be clamped by internal diodes. Current should be limited to the maximum ratings given.

## CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADG751 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD


Table I. Truth Table

| ADG751 IN | Switch Condition |
| :--- | :--- |
| 0 | ON |
| 1 | OFF |

## ADG751-Typical Performance Characteristics



Figure 1. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ Single Supplies (A Grade)


Figure 2. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures $V_{D D}=3 V(A$ Grade)


Figure 3. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures $V_{D D}=5$ V (A Grade)


Figure 4. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ Single Supplies (B Grade)


Figure 5. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures $V_{D D}=3 V(B$ Grade)


Figure 6. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures $V_{D D}=5 \mathrm{~V}$ (B Grade)


Figure 7. On Response vs. Frequency (A Grade)


Figure 8. On Response vs. Frequency (B Grade)


Figure 9. Off Isolation vs. Frequency for Both Grades


Figure 10. Supply Current vs. Input Switching Frequency


Figure 11. Charge Injection vs. Source/Drain Voltage

## ADG751

## GENERAL DESCRIPTION

The ADG751 is an SPST switch constructed using switches in a T configuration to obtain high "OFF" isolation while maintaining good frequency response in the "ON" condition.
Figure 12 shows the T-switch configuration. While the switch is in the OFF state, the shunt switch is closed and the two series switches are open. The closed shunt switch provides a signal path to ground for any of the unwanted signals that find their way through the off capacitances of the series' MOS devices. This results in improved isolation between the input and output than with an ordinary series switch. When the switch is in the ON condition, the shunt switch is open and the signal path is through the two series switches which are now closed.


Figure 12. Basic T-Switch Configuration

## LAYOUT CONSIDERATIONS

Where accurate high frequency operation is important, careful consideration should be given to the printed circuit board layout and to grounding. Wire wrap boards, prototype boards and sockets are not recommended because of their high parasitic inductance and capacitance. The part should be soldered directly to a printed circuit board. A ground plane should cover all unused areas of the component side of the board to provide a low impedance path to ground. Removing the ground planes from the area around the part reduces stray capacitance.
Good decoupling is important in achieving optimum performance. $\mathrm{V}_{\mathrm{DD}}$ should be decoupled with a $0.1 \mu \mathrm{~F}$ surface mount capacitor to ground mounted as close as possible to the device itself.

## Test Circuits



Test Circuit 1. On Resistance


Test Circuit 2. Off Leakage


Test Circuit 3. On Leakage


Test Circuit 4. Switching Times


Test Circuit 5. Charge Injection


Test Circuit 6. Off Isolation


Test Circuit 7. Bandwidth

## ADG751

## OUTLINE DIMENSIONS



Figure 12. 8-Lead Mini Small Outline Package [MSOP] (RM-8)
Dimensions shown in millimeters


COMPLIANT TO JEDEC STANDARDS MO-178-AB
Figure 13. 6-Lead Small Outline Transistor Package [SOT-23] (RJ-6)
Dimensions shown in millimeters

## ADG751

ORDERING GUIDE

| Model $^{1}$ | Temperature Range | Brand $^{2}$ | Package Description | Package Option |
| :--- | :--- | :--- | :--- | :--- |
| ADG751BRMZ-REEL | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDB | 8-Lead Mini Small Outline Package [MSOP] | RM-8 |
| ADG751BRT-REEL | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDB | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |
| ADG751BRT-REEL7 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDB | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |
| ADG751BRTZ-REEL7 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDB | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |
| ADG751ARMZ | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDA | 8-Lead Mini Small Outline Package [MSOP] | RM-8 |
| ADG751ARMZ-REEL | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDA | 8-Lead Mini Small Outline Package [MSOP] | RM-8 |
| ADG751ART-REEL | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDA | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |
| ADG751ART-REEL7 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDA | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |
| ADG751ARTZ-REEL7 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | SDA | 6-Lead Small Outline Transistor Package [SOT-23] | RJ-6 |

${ }^{1} Z=$ RoHS Compliant Part.
${ }^{2}$ Brand on these packages is limited to three characters due to space constraints.

## REVISION HISTORY

8/12-Rev. 0 to Rev. A
Updated Outline Dimensions
Changes to Ordering Guide 11
4/99-Revision 0-Initial Version

## X-ON Electronics

Largest Supplier of Electrical and Electronic Components
Click to view similar products for Analogue Switch ICs category:
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Other Similar products are found below :
FSA3051TMX NLAS4684FCTCG NLAS5223BLMNR2G NLVAS4599DTT1G NLX2G66DMUTCG 425541DB 425528R 099044FB NLAS5123MNR2G PI5A4599BCEX NLAS4717EPFCT1G PI5A3167CCEX SLAS3158MNR2G PI5A392AQE PI5A4157ZUEX PI5A3166TAEX FSA634UCX TC4066BP(N,F) DG302BDJ-E3 PI5A100QEX HV2605FG-G HV2301FG-G RS2117YUTQK10 RS2118YUTQK10 RS2227XUTQK10 ADG452BRZ-REEL7 MAX4066ESD+ MAX391CPE+ MAX4730EXT+T MAX314CPE+ BU4066BCFV-E2 MAX313CPE+ BU4S66G2-TR NLAS3158MNR2G NLASB3157MTR2G TS3A4751PWR NLAS4157DFT2G NLAS4599DFT2G NLAST4599DFT2G NLAST4599DTT1G DG300BDJ-E3 DG2503DB-T2-GE1 DG2502DB-T2-GE1

TC4W53FU(TE12L,F) 74HC2G66DC. 125 ADG619BRMZ-REEL ADG1611BRUZ-REEL7 LTC201ACN\#PBF 74LV4066DB,118
FSA2275AUMX

